

PATENT ABSTRACTS OF JAPAN

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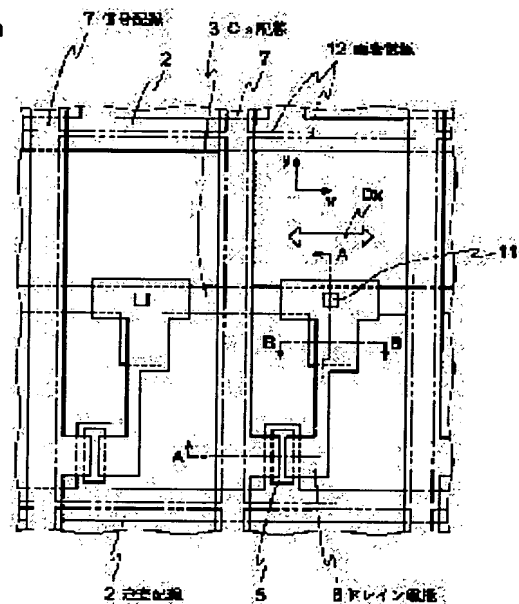
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(54) LIQUID CRYSTAL DISPLAY DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To prevent the degradation in display quality, such as flickering occurring in the fluctuation with each of exposure regions, image persistence and display unevenness, by compensating the fluctuation in ΔC_{gd} by the fluctuation in C_{gd} generated with each of the exposure regions by changing a C_s value with each of the exposure regions.

SOLUTION: The C_{gd} changes when a drain electrode 8 deviates relatively in an x-axis direction D_x with respect to scanning wiring 2. If the drain electrode 8 deviates relatively in a $-x$ direction with respect to the scanning wiring 2, the overlap area of the drain electrode 8 and the scanning wiring 2 increases and the C_{gd} increases. Conversely, if the drain electrode 8 deviates relatively in a $+x$ direction with respect to the scanning wiring 2, the overlap area of the drain electrode 8 and the scanning wiring 2 decreases and the C_{gd} decreases. Then, the shapes of the drain electrode 8 and C_s wiring 3 in a B-B line part are so designed that $\Delta V_{gd} = (C_{gd} \times \Delta V_g) / (C_{gd} + C_s + C_{lc})$ is kept constant in spite of the fluctuation in the C_{gd} .



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